

## Search Notes



**Application/Control No.**

10/759,339

**Examiner**

Hiep Nguyen

**Applicant(s)/Patent under  
Reexamination**

BECKER ET AL.

## Art Unit

2816

SEARCHED

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**